Special Issue

Latest Research on Electronic Noise

Message from the Guest Editor

Electronic noise has often been considered a problem, and is seen as a disturbance to be eliminated or, at least, reduced as much as possible.However, having its origins in the interaction between matter and charged particles and carrying information about the phenomena that occur at the microscopic level, it can give useful information on the structure of the device under test (DUT) or on its working mechanisms. In this sense, therefore, measuring noise is a powerful device and material characterization technique. This Special Issue aims to collect works that address noise from different points of view: as a knowledge tool or as an issue to be controlled and reduced. Physical interpretations, models, applications, dedicated instrumentation, and measurements are among the topics that we intend to explore.

Guest Editor

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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